

[54] MICROMETER

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[73] Assignee: Mitutoyo Manufacturing Company, Ltd., Tokyo, Japan

[**] Term: 14 Years

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[30] Foreign Application Priority Data

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[52] U.S. Cl. D10/73

[58] Field of Search D10/73; 33/143 R, 143 A, 33/143 B, 143 C, 143 M, 143 J, 143 K

[56] References Cited

U.S. PATENT DOCUMENTS

D. 136,578 10/1943 Reed D10/73
3,241,241 3/1966 Müller 33/143 R

OTHER PUBLICATIONS

Mitutoyo Cat. #900-p. 25-outside Micrometer.
Mitutoyo Cat. #900-p. 38-inside Micrometer.

Primary Examiner—Nelson C. Holtje
Attorney, Agent, or Firm—William L. Androlia

[57] CLAIM

The ornamental design for a micrometer, substantially as shown and described.

DESCRIPTION

FIG. 1 is a front perspective view of a micrometer showing my new design;
FIG. 2 is a front elevational view thereof;
FIG. 3 is a rear elevational view thereof;
FIG. 4 is a top plan view thereof;
FIG. 5 is a bottom plan view thereof;
FIG. 6 is a left side elevational view thereof;
FIG. 7 is a right side elevational view thereof;
FIG. 8 is a cross-sectional view thereof as taken from line VIII—VIII of FIG. 4.

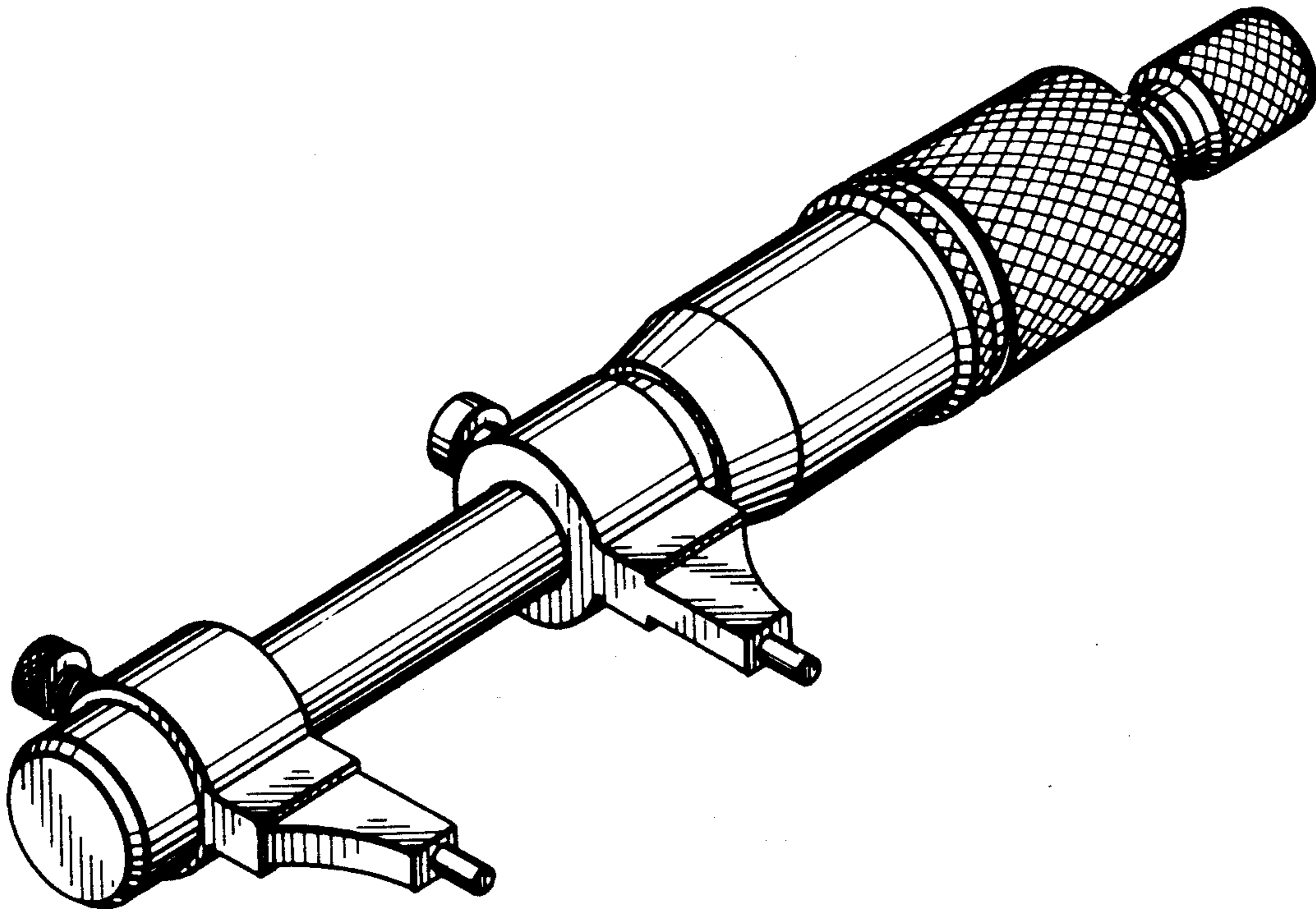


FIG. 1

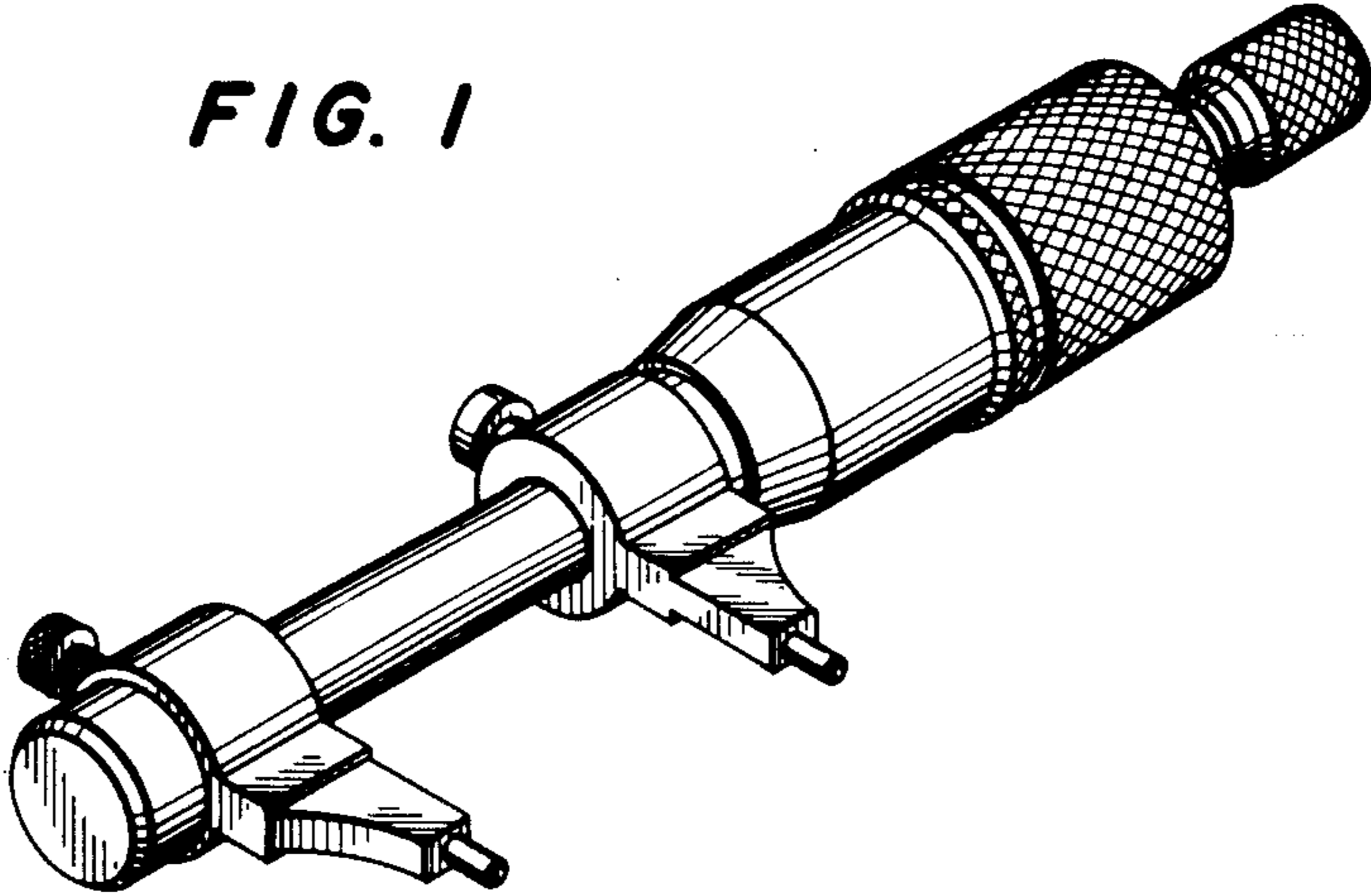


FIG. 2

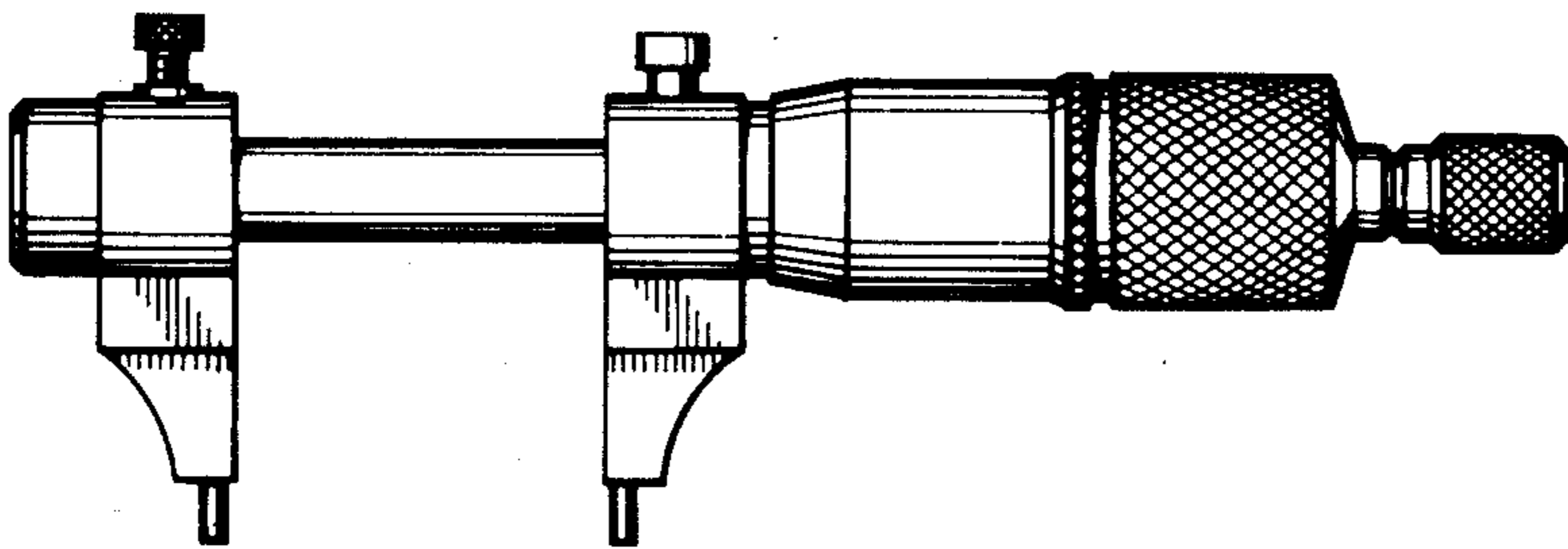


FIG. 3

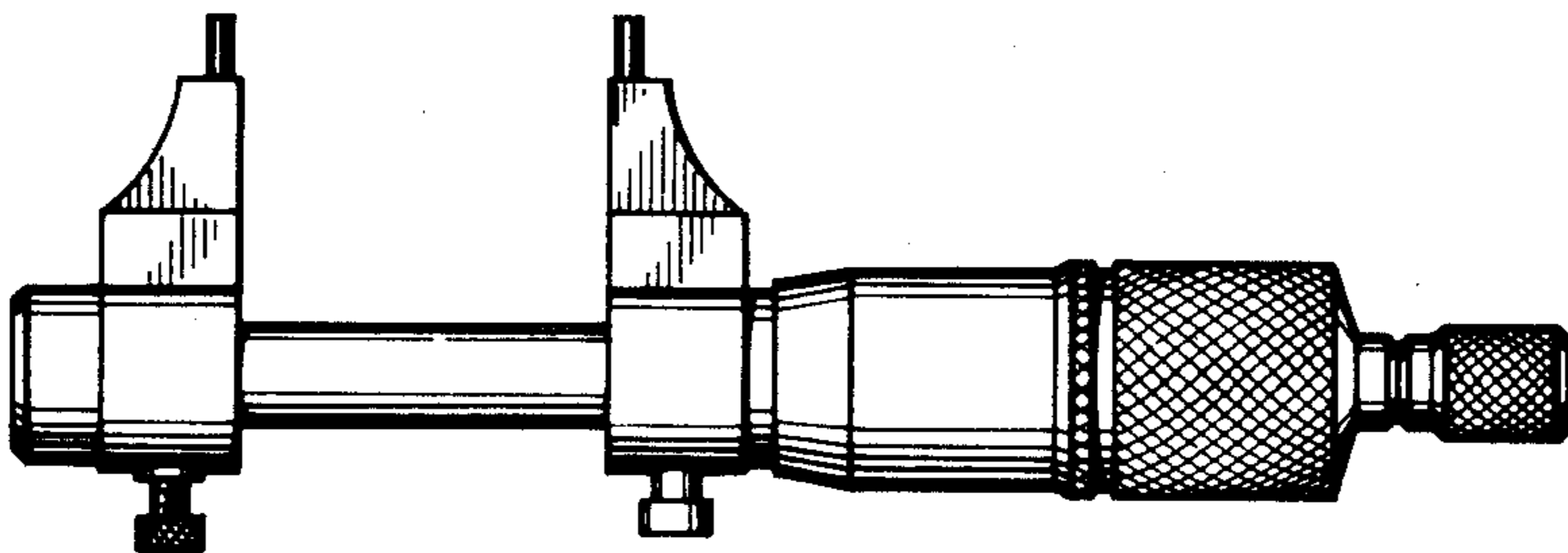


FIG. 4

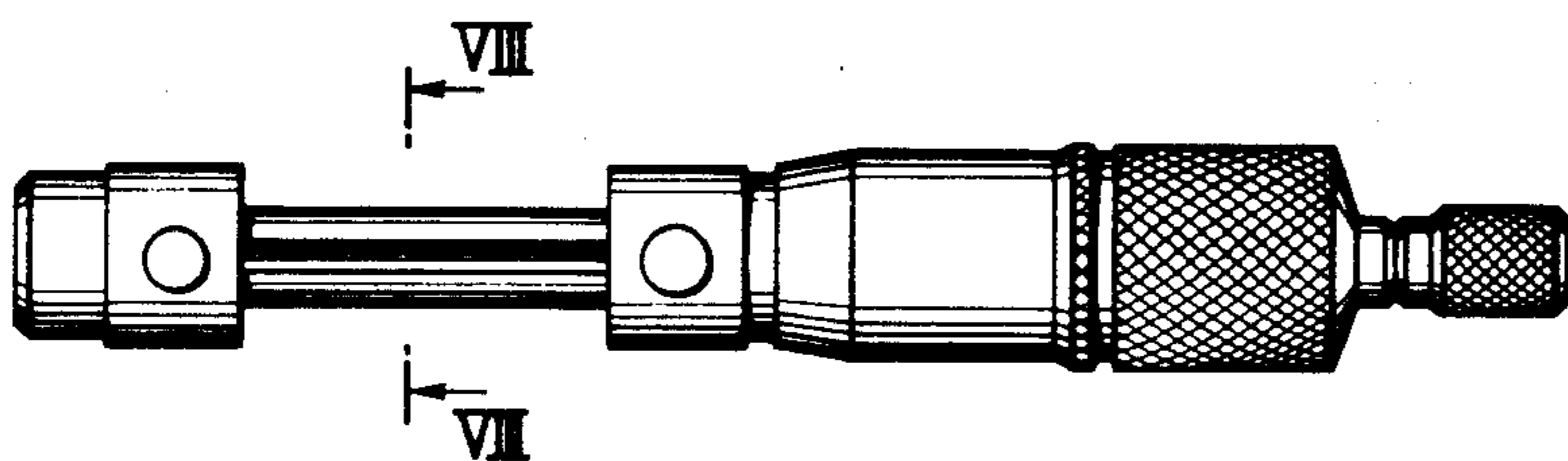


FIG. 5



FIG. 6



FIG. 7

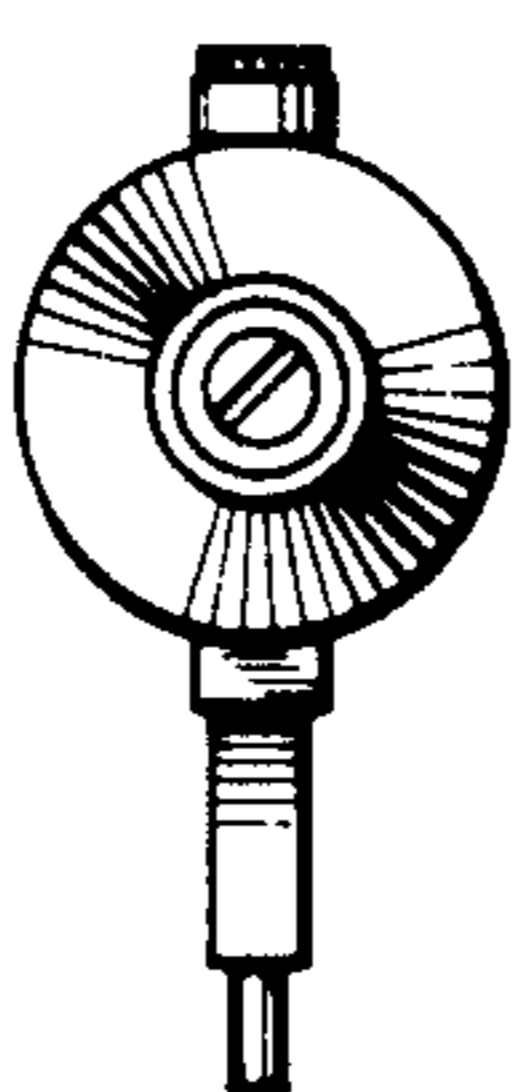


FIG. 8

